

**PATENT APPLICATION**  
**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of

Docket No: Q79846

Ralf LINDNER, et al.

Appln. No.: Not Yet Assigned

Confirmation No.: Not Yet Assigned

Group Art Unit: Not Yet Assigned

Filed: February 23, 2004

Examiner: Not Yet Assigned

For: METHOD FOR PRODUCING RADIATION-RESISTANT QUARTZ GLASS  
MATERIAL, AND QUARTZ GLASS MATERIAL

**INFORMATION DISCLOSURE STATEMENT**  
**UNDER 37 C.F.R. §§ 1.97 and 1.98**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure under 37 C.F.R. § 1.56, Applicant hereby notifies the U.S. Patent and Trademark Office of the documents which are listed on the attached PTO/SB/08 A & B (modified) form and/or listed herein and which the Examiner may deem material to patentability of the claims of the above-identified application.

One copy of each of the listed documents, other than any U.S. patents and patent publications, is submitted herewith.

The present Information Disclosure Statement is being filed: (1) No later than three months from the application's filing date; (2) Before the mailing date of the first Office Action on the merits (whichever is later); or (3) Before the mailing date of the first Office Action after filing a request for continued examination (RCE) under §1.114, and therefore, no Statement under 37 C.F.R. § 1.97(e) or fee under 37 C.F.R. § 1.17(p) is required.

INFORMATION DISCLOSURE STATEMENT

U.S. Appln. No.: Not Yet Assigned

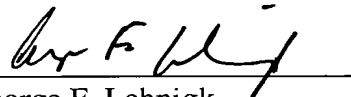
Attorney Docket No.: Q79846

In compliance with the concise explanation requirement under 37 C.F.R. § 1.98(a)(3) for foreign language documents, Applicant encloses herewith a copy of a Search Report from a foreign patent office in a counterpart application citing such documents, together with an English-language version (if not already included) of at least that portion of the Search Report indicating the degree of relevance found by the foreign patent office. In addition, concise statements of relevance for certain ones of the documents being submitted are found in the specification of the above-identified application.

The submission of the listed documents is not intended as an admission that any such document constitutes prior art against the claims of the present application. Applicant does not waive any right to take any action that would be appropriate to antedate or otherwise remove any listed document as a competent reference against the claims of the present application.

The USPTO is directed and authorized to charge all required fees, except for the Issue Fee and the Publication Fee, to Deposit Account No. 19-4880. Please also credit any overpayments to said Deposit Account. A duplicate copy of this paper is attached.

Respectfully submitted,



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WASHINGTON OFFICE

**23373**

CUSTOMER NUMBER

GFL/plr

Date: February 23, 2004

Substitute for Form 1449 A & B/PTO  <b><u>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</u></b>  <i>(use as many sheets as necessary)</i>				<i>Complete if Known</i>	
				Application Number	Not Yet Assigned
				Confirmation Number	Not Yet Assigned
				Filing Date	February 23, 2004
				First Named Inventor	Ralf LINDNER
				Art Unit	Not Yet Assigned
				Examiner Name	Not Yet Assigned
Sheet	1	of	1	Attorney Docket Number	Q79846

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code <sup>2</sup> (if known)		
		US 5,325,230	A	6/28/1994	Shigeru YAMAGATA, et al
		US 5,086,352	A	2/4/1992	Shigeru YAMAGATA, et al
		US 6,295,841	B1	10/2/2001	Douglas C. ALLAN, et al
		US 6,205,818	B1	3/27/2001	Thomas P. SEWARD, III
		US 6,550,277			(corresponds to DE 100 05 051)

FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation <sup>6</sup>
		Country Code <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> (if known)			
		DE	199 42 443	A1	3/9/2000	TOSOH CORP.	
		DE	690 15 453	T2	6/1/1995	HERAEUS QUARZGLAS GMBH	
		EP	1 084 995	A1	3/21/2001	HERAEUS QUARZGLAS GMBH & CO. KG	
		JP	63129034	A	6/1/1988	FUJIKURA LTD	ABSTRACT
		JP	08002937	A	1/9/1996	SHINETSU QUARTZ PROD CO.	ABSTRACT
		JP	04-097922	A	3/30/1992	SHINETSU QUARTZ PROD CO.	ABSTRACT
		JP	03088742	A	4/15/1991	SHINETSU SEKIEI KK	ABSTRACT
		JP	03023236	A	1/31/1991	SHINETSU SEKIEI KK	ABSTRACT
		JP	01197343	A	8/9/1989	SHINETSU SEKIEI KK	ABSTRACT
		JP	01197335	A	8/9/1989	SHINETSU SEKIEI KK	ABSTRACT
		DE	100 05 051	A1	5/31/2001	HERAEUS QUARZGLAS GMBH	
		JP	03088743	A	4/15/1991	SHINETSU SEKIEI KK	ABSTRACT
		JP	2001089170	A	4/3/2001	SHINETSU QUARTZ PROD CO.	ABSTRACT

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation <sup>6</sup>
		J.E. SHELBY, "RADIATION EFFECTS IN HYDROGEN-IMPREGNATED VITREOUS SILICA", J. APPL. PHYS. VOL. 50, NO. 5, 1979 AMERICAN INSTITUTE OF PHYSICS, PAGES 3702-3706, MAY 1979, SANDIA LABORATORIES, LIVERMORE, CALIFORNIA	
		C.K. VAN PESKI, ET AL "BEHAVIOR OF FUSED SILICA IRRADIATED BY LOW LEVEL 193NM EXCIMER LASER FOR TENS OF BILLIONS OF PULSES", PROC. SPIE VOL. 4347, PAGES 177-186, 2001, AUSTIN TEXAS 78741	
		DAVID L. GRISCOM, "OPTICAL PROPERTIES AND STRUCTURE OF DEFECTS IN SILICA GLASS", JOURNAL OF THE CERAMIC SOCIETY OF JAPAN, INT. EDITION, NAVAL RESEARCH LABORATORY, WASHINGTON DC.	
		HIROYUKI NISHIKAWA, ET AL, "GENERATION MECHANISM OF PHOTOINDUCED PARAMAGNETIC CENTERS FORM PREEXISTING PRECURSORS IN HIGH-PURITY SILICAS", THE AMERICAN PHYSICAL SOCIETY, VOLUME 41, NUMBER 11, PAGES 7828-7834, April 15, 1990-I, TOKYO JAPAN.	
Examiner Signature		Date Considered	

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup>Applicant's unique citation designation number (optional). <sup>2</sup>See Kind Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov), MPEP 901.04 or follow the hyperlink from the title of the document to the intranet. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST. 3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup>Applicant is to indicate here if English language Translation is attached.